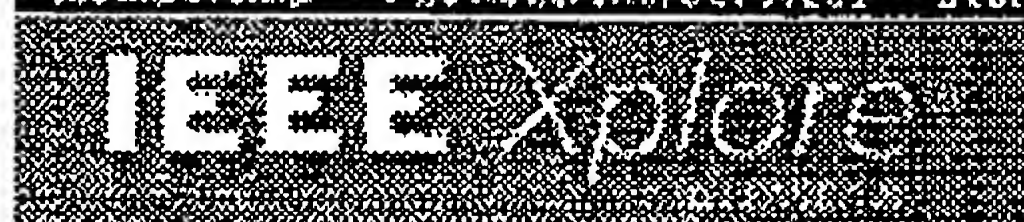
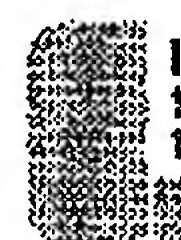


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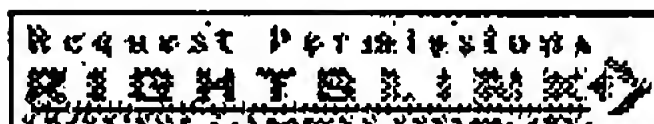
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On-chip repair and an ATE independent fusing methodology

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This paper appears in: Test Conference, 2002. Proceedings. International

Publication Date: 7-10 Oct. 2002

On page(s): 178 - 186

ISSN: 1089-3539

Number of Pages: xvi+1250

Inspec Accession Number: 7528786

Abstract:

This paper describes a novel on chip repair system designed for ATE independent application on many unique very dense ASIC devices in a high turnover environment. During test, the system controls on chip built-in self-test (BIST) engines, collects compresses repair data, programs fuses and finally decompresses and reloads the data for post fuse testing. In end use applications this system decompresses the repair data at power-up or at the request of the system.

Index Terms:

[application specific integrated circuits](#) [automatic test equipment](#) [built-in self test](#) [electrical integrated circuit testing](#) [maintenance engineering](#) [ASIC on-chip repairs](#) [ATE independent methodology](#) [BIST](#) [built-in self-test engines](#) [e-fuse programming](#) [electrically programmable high turnover environment](#) [on chip repair systems](#) [post fuse testing](#) [repair data collection/compression](#) [repair data decompression/reloading](#) [unique very dense ASIC](#)

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